

Substitute Form PTO-1449 (Modified)		U.S. Department of Commerce Patent and Trademark Office		Attorney's Docket No. 07977/279001/US5023/5025	Application No.
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Yamazaki, et al.			
		Filing Date June 25, 2001	Group Art Unit		

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 09/09/01
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 06/25/01

U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
M>	AA	5,643,826	7/1/97	Ohtani, et al.			
M>	AB	5,923,962	7/13/99	Ohtani, et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
M>	AL ✓	07-130652	5/19/95	Japan			Abstract only
M>	AM ✓	08-078329	3/22/96	Japan			Abstract only
	AN						
	AO						
	AP						

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
M>	AQ ✓	Ishihara, et al., "Microtexture Analysis of Location Controlled Large Si Grain Formed by Excimer-Laser Crystallization Method", AM-LCD 99, Digest of Technical Papers, pp. 99-102, July 1999, Tokyo, Japan.
	AR	
	AS	
	AT	

Examiner Signature <i>Matthew S.</i>	Date Considered <i>12/12/2001</i>
EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified) DEC 26 2001 (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-279001	Application No. 09/892,225
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Yamazaki, et al.	
		Filing Date June 25, 2001	Group Art Unit 2811

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
MS	AQ ✓	U.S. Serial No. 09/874,204, filed June 6, 2001 entitled "Thin Film Transistors and Semiconductor Device", Specification 44 pages; 132 Claims; Abstract 1 page; Drawings 24 Figs.
↓	AR ✓	U.S. Serial No. 09/880,089, filed June 14, 2001 entitled "Semiconductor Device", Specification 65 pages; 50 Claims; Abstract 1 page; Drawings 45 Figs.
↓	AS ✓	U.S. Serial No. 09/882,265, filed June 18, 2001 entitled "Semiconductor Device", Specification 100 pages; 52 Claims; Abstract 1 page; Drawings 32 Figs.
	AT	

Examiner Signature <i>Matthew S. Son</i>	Date Considered <i>12/17/2001</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	